

10/630,957

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|--|------------------------------|------------------|---------|------------------|
| L1 | 0 | (coding test pattern AND scan design AND build-in test hardware AND (BIT-HW) AND BIST AND linear feedback shift register AND LFSR AND pseudo-random pattern generator AND scan chain AND computer program AND test vector AND compressed test vector AND logic model AND function operator AND initial state-function AND executable logic model AND LFSR generator matrix AND iterative execution AND chain access operator).clm. | US-PGPUB; USPAT; USOCR | ADJ | ON | 2006/12/30 11:20 |

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|--------|--|--|------------------|---------|------------------|
| L1 | 0 | (coding test pattern AND scan design AND build-in test hardware AND (BIT-HW) AND BIST AND linear feedback shift register AND LFSR AND pseudo-random pattern generator AND scan chain AND computer program AND test vector AND compressed test vector AND logic model AND function operator AND initial state-function AND executable logic model AND LFSR generator matrix AND iterative execution AND chain access operator).clm. | US-PGPUB; USPAT; USOCR | ADJ | ON | 2006/12/30 11:27 |
| L2 | 8636 | IC built-in self test hardware or (BIST) or built-in self test or built-in test or built-in self test hardware or BIT-HW | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:29 |
| L3 | 725336 | automatic test pattern generation or (ATPG) or automatic test pattern generator or software | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:30 |
| L4 | 477747 | external automatic test equipment or ATE | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:31 |
| L5 | 3274 | I2 and I3 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:31 |
| L6 | 364 | I4 and I5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:31 |

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| L7 | 4047 | scan chain\$1 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:31 |
| L8 | 212 | compress\$3 same test vector\$1 or compressed test vector | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:49 |
| L9 | 1 | LFSR generator matrix | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:50 |
| L10 | 1 | initial state-function | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:50 |
| L11 | 207 | iterative execution | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:50 |
| L12 | 4608 | function operator | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:50 |
| L13 | 378730 | compressor | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:50 |

EAST Search History

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| L14 | 14 | state-function\$1 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:51 |
| L15 | 988 | logic model\$1 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:51 |
| L16 | 1 | chain access operator\$1 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:52 |
| L17 | 79 | physical BIT-HW or BIT-code or built-in test code | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:54 |
| L18 | 364 | I5 and I6 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:55 |
| L19 | 163 | I18 and I7 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:55 |
| L20 | 16 | I19 and I8 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 12:28 |

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| L21 | 1 | I20 and I11 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:56 |
| L22 | 1 | I20 and I12 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 12:26 |
| L23 | 1 | I20 and I13 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:57 |
| L24 | 1 | I20 and I14 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:56 |
| L25 | 1 | I20 and I15 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:56 |
| L26 | 1 | I20 and I17 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 11:56 |
| L27 | 9458 | 714/733 or 714/734 or 714/726 or 714/725 or 714/724 or 714/727 or 714/729 or 714/728 or 714/738 or 714/739 or 714/30 or 716/4 or 714/37 or 714/? | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 12:30 |

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| L28 | 13 | I20 and I27 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/12/30 12:30 |
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